

Nanostrutture a base di Si e Ge per nuovi dispositivi nano-elettronici

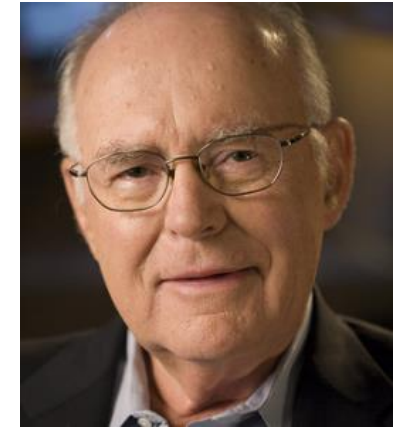
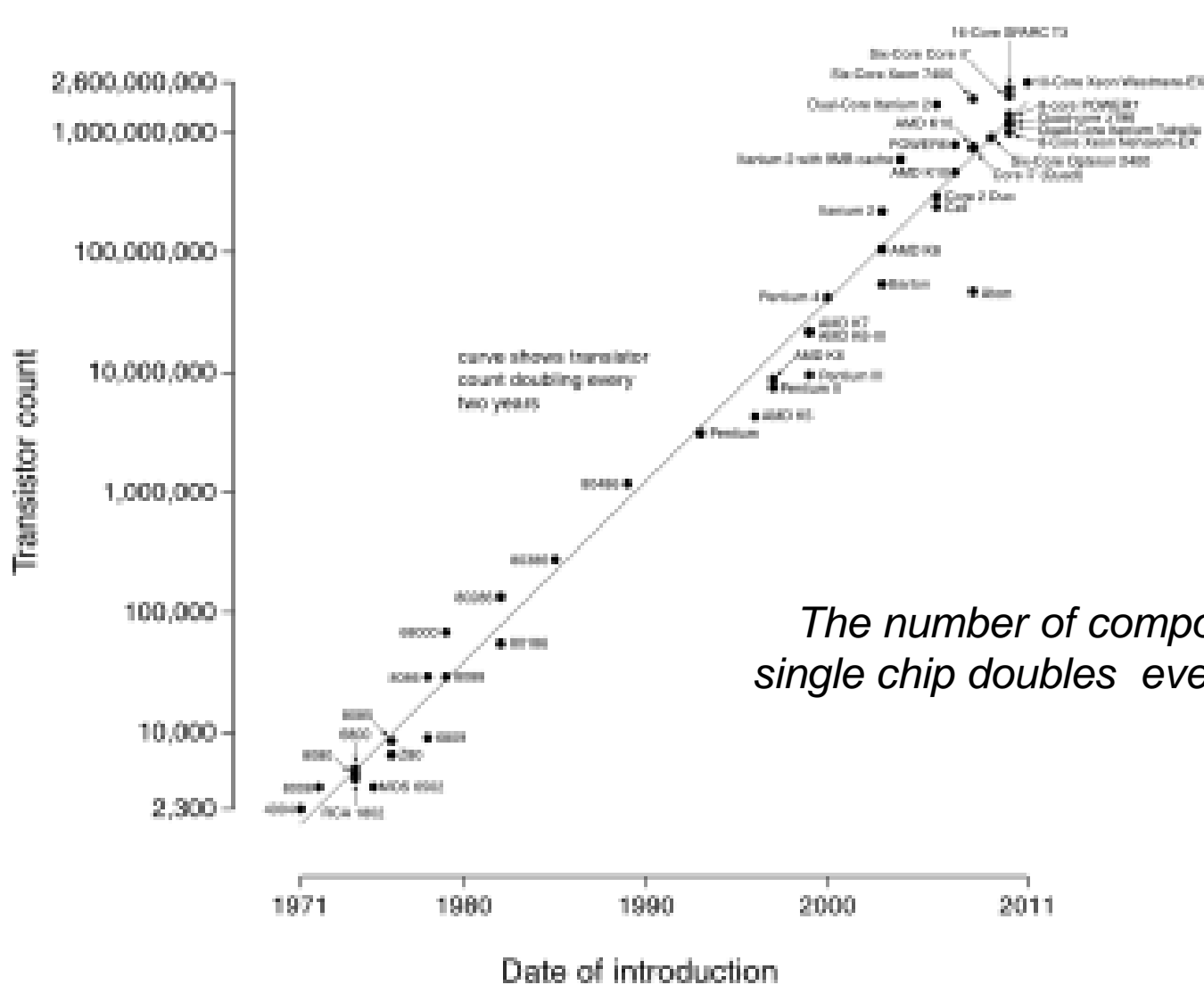
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Laboratorio MDM, IMM-CNR
Agrate Brianza (Italy) – www.mdm.imm.cnr.it

Plan of the talk

- Scaling down electronic devices (Moore's law)
- P or Se doped Si-nanowires for quantum computing
- Delocalization of P(Se) wave-function Si NW [001], [011], [111] oriented
- Ab initio spectroscopy (Hyperfine parameters, MOKE)
- Conclusion and Discussion

Scaling down of CMOS logic devices

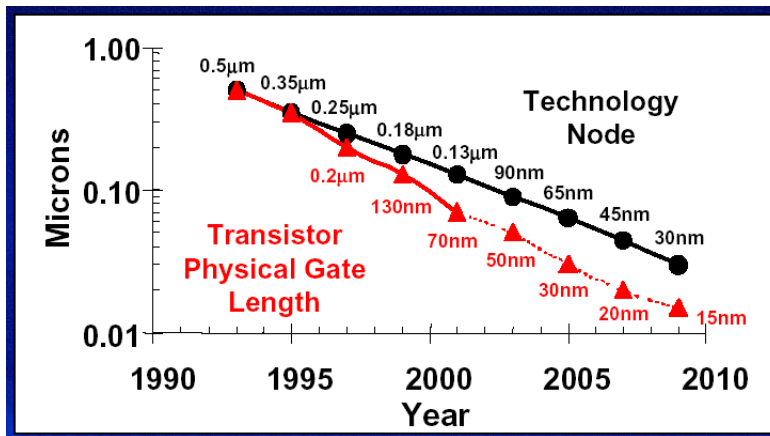
Microprocessor Transistor Counts 1971-2011 & Moore's Law



Moore's law

The number of components in a single chip doubles every 18 months

Scaling down of CMOS logic devices



INTEL Presentation SPIE 03/2003

La dimensione dei chip si riduce costantemente ...

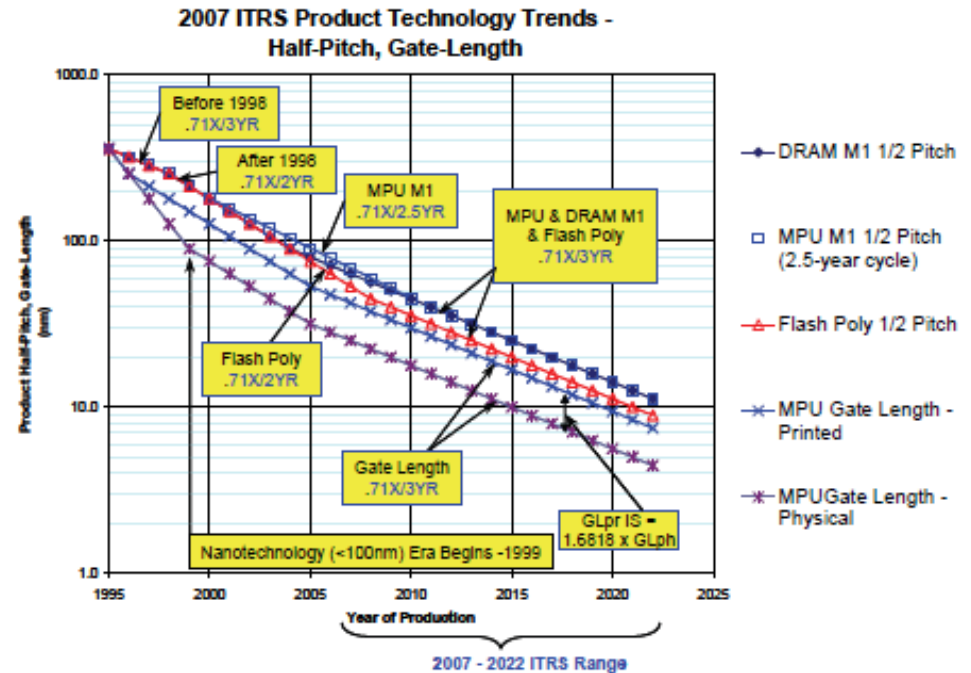
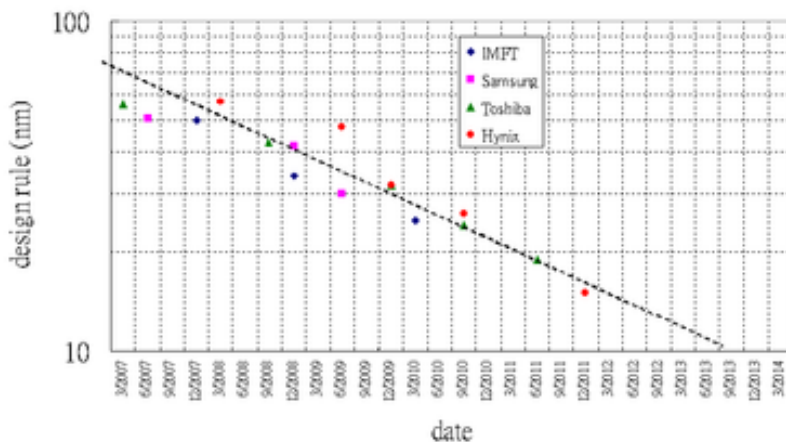


Figure 7 2007 ITRS—Half Pitch and Gate Length Trends

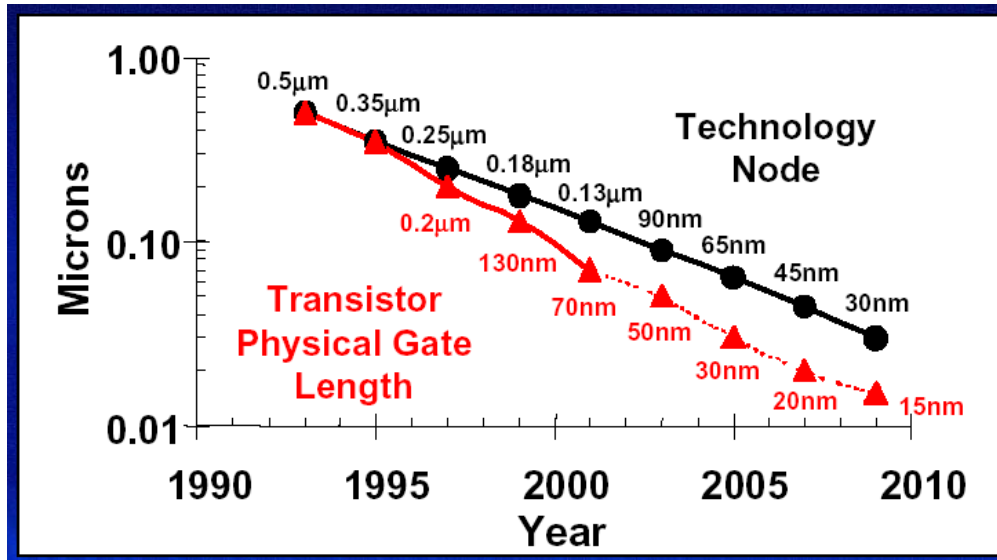
International Technology Roadmap for Semiconductors (ITRS)

<http://www.itrs.net/>

... fino a raggiungere le dimensioni atomiche ?!



Scaling down of electronic devices



Three strategies

Ultra-scaled
CMOS devices

More than Moore, new
concept for ultra-
scaled devices

Moore's law

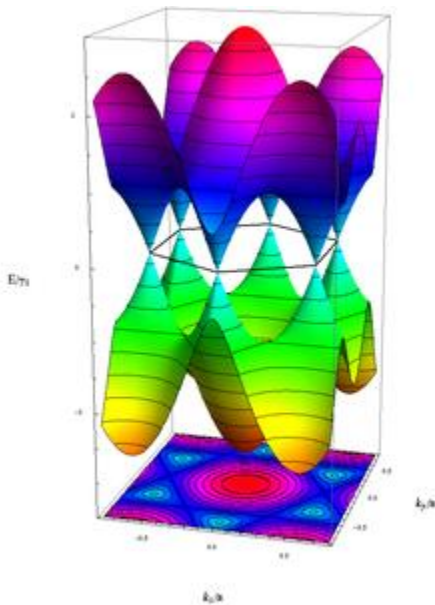
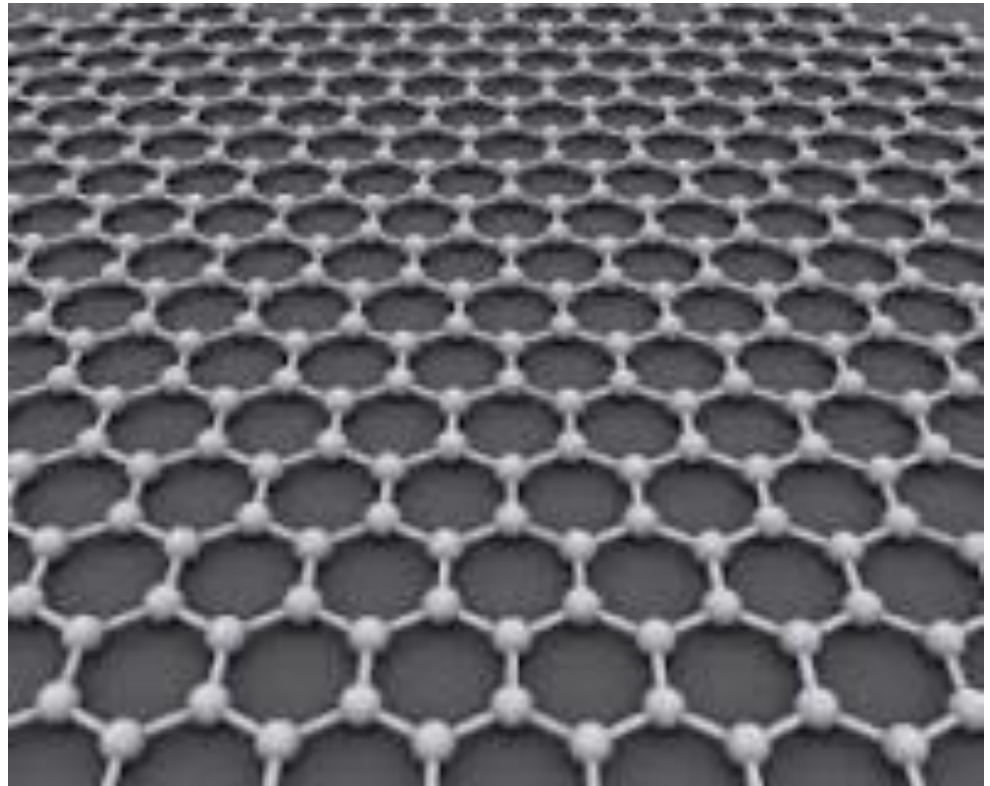
Nanodevices whose size
is a few nanometers

Quantum effect are
relevant → first principles
simulations techniques

Nano structures as
building block of novel
device

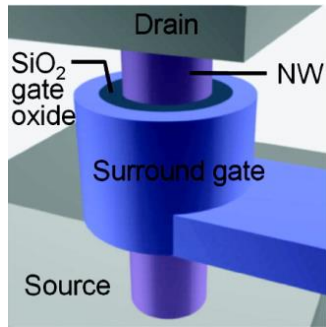
Il nuovo mondo bidimensionale

- Grafene (C)
- Silicene (Si)
- Germanene (Ge)
- Stanene (Sn)



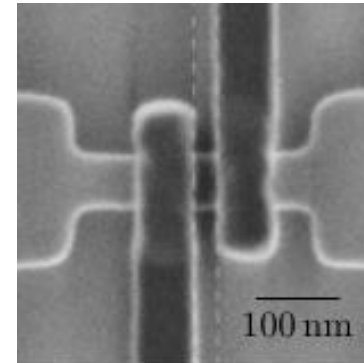
Dispositivi ultra-veloci
Nuovi Sensori
Nuova elettronica

Si-Nanostructures Applications



Ultra-scaled
electronic devices

Gate controlled
quantum dot



Photovoltaics



Nanosensors (DNA, ...)



Quantum computation



- What are the limits of Conventional computing ?

Density Functional Theory

For a give external potential

Target:
to compute the total energy

$$v(\vec{r}) \rightarrow E[n]$$

Total energy is a unique functional of the density

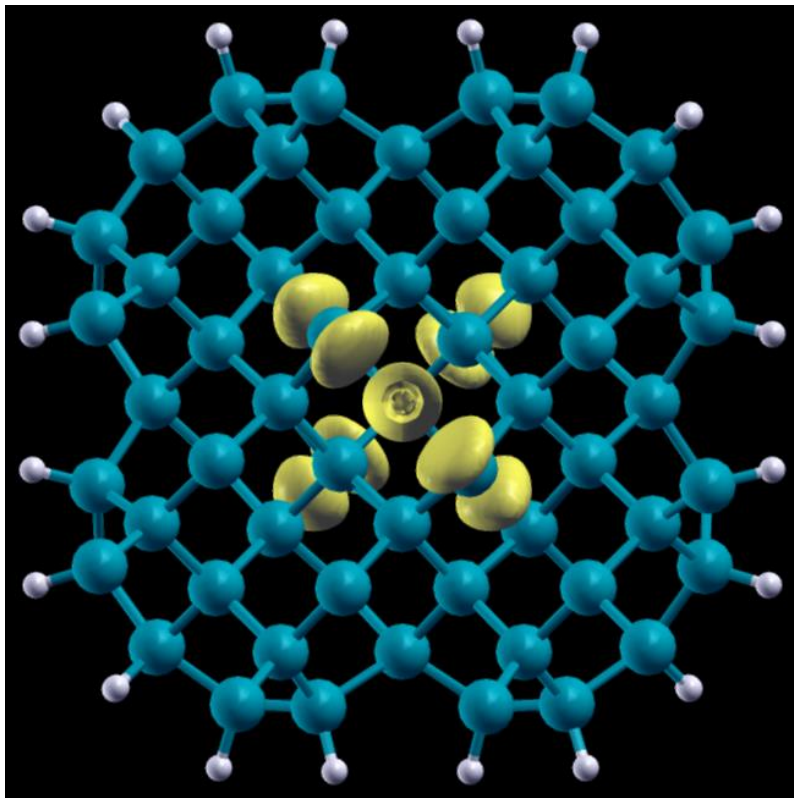
Plane-waves pseudo-potential techniques

$$E[n] = \sum \varepsilon_v - \frac{1}{2} \int \frac{n(\vec{r})n(\vec{r}')}{|\vec{r} - \vec{r}'|} d\vec{r} d\vec{r}' + E_{xc}[n] - \int v(\vec{r})n(\vec{r})d\vec{r}$$

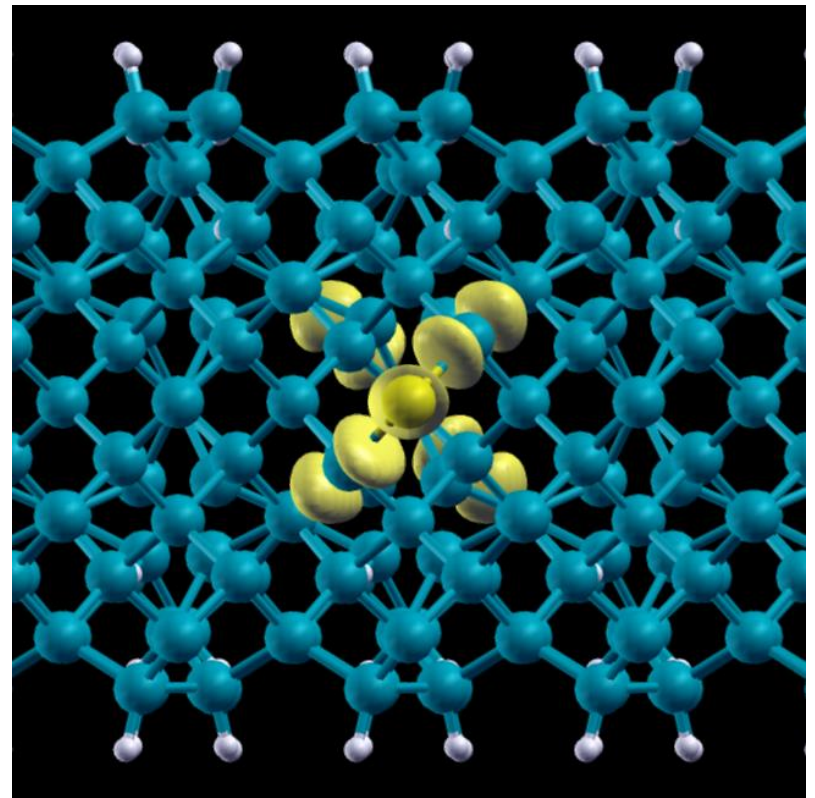
Ab initio: Simulazioni senza alcun parametro sperimentale !!!

Single atom electronics: Se impurity

Se doped H passivated Si nanowires
(nanoelectronics, quantum computer)

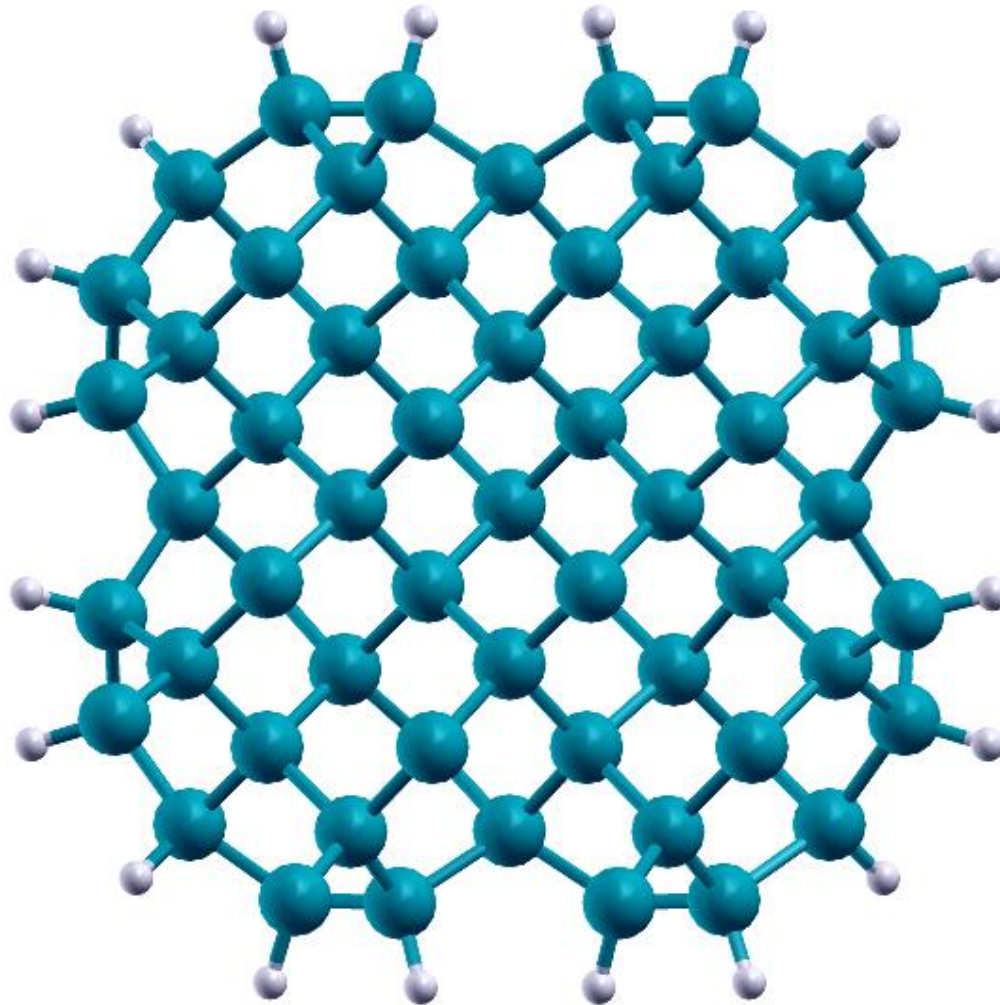


front view



side view

Nanowire passivation



H passivated Si nanowires

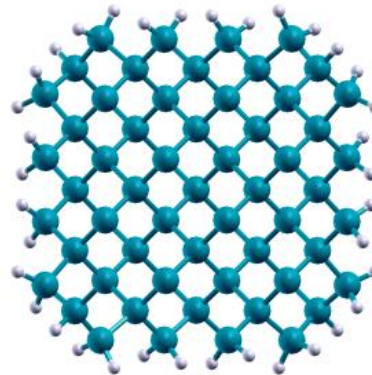
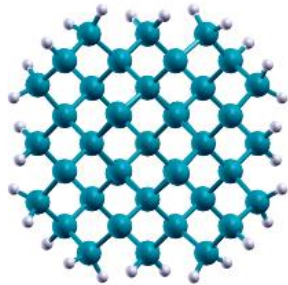
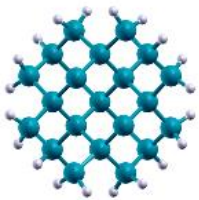
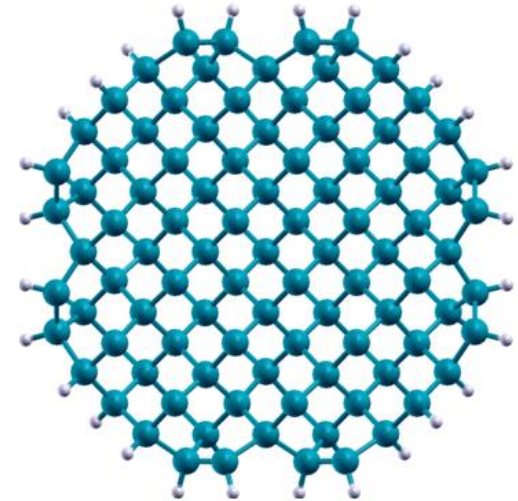
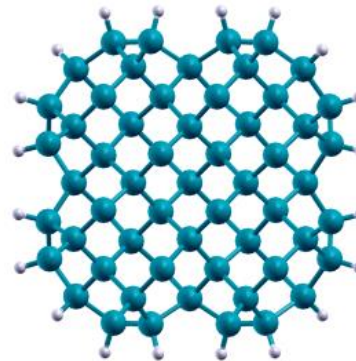
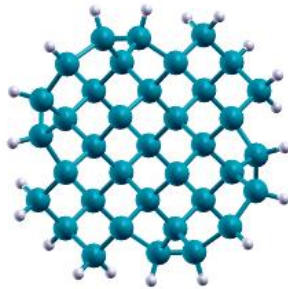
$d \simeq 0.8$ nm

$d \simeq 1.2$ nm

$d \simeq 1.5$ nm

$d \simeq 2$ nm

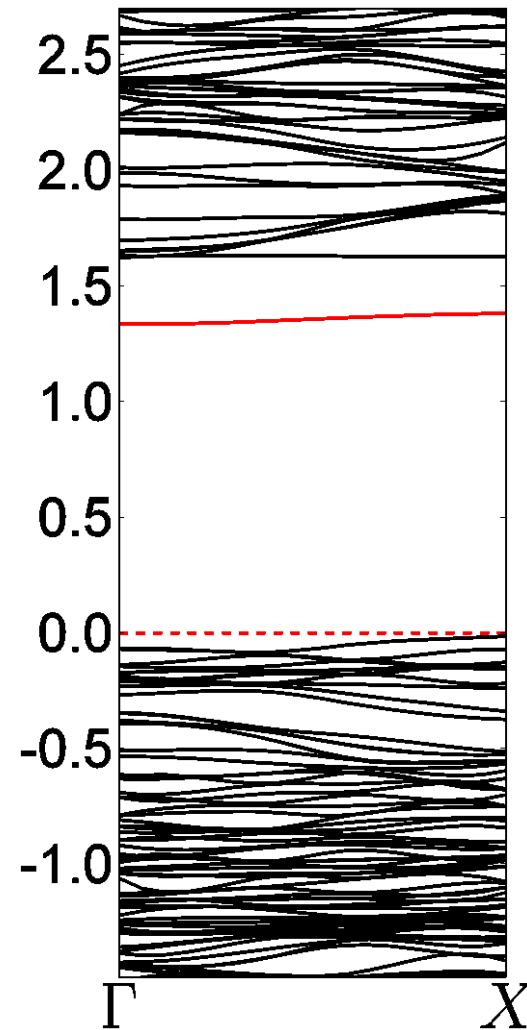
Relaxed –
Passivated and
Relaxed again
Distortion of NW
for small size is
significant.



Passivated and relaxed

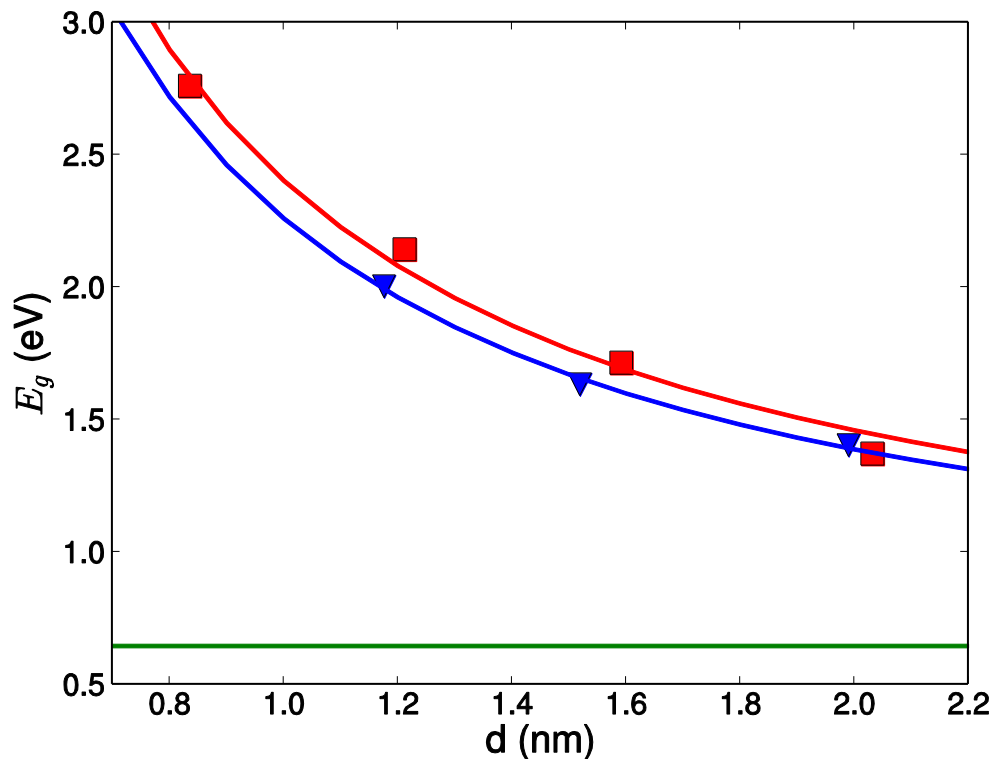
Se doped Si nanowires

- One dimensional bandstructure
- Impurity level in the bandgap
- Correction to periodically repeated charged images (Rurali et al, Makov-Payne)



Band-gap of Si nano-wire

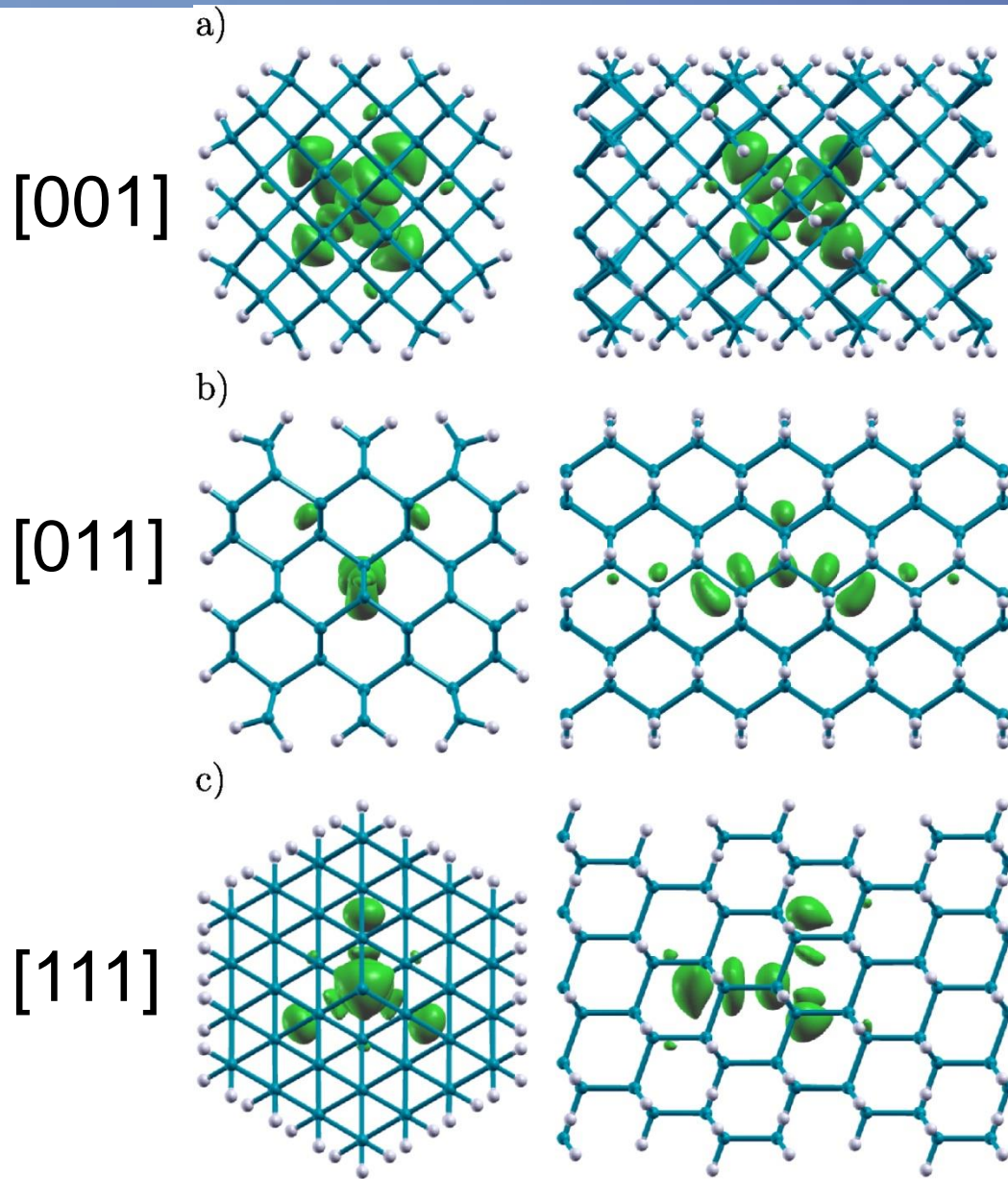
Band-gap as a function of NW diameter



- Triangles: NW with surface reconstruction
- Squares: NW without surface reconstruction

As an effect of confinement the Bandgap increases as the diameter is reduced

Delocalization of donor wave-function

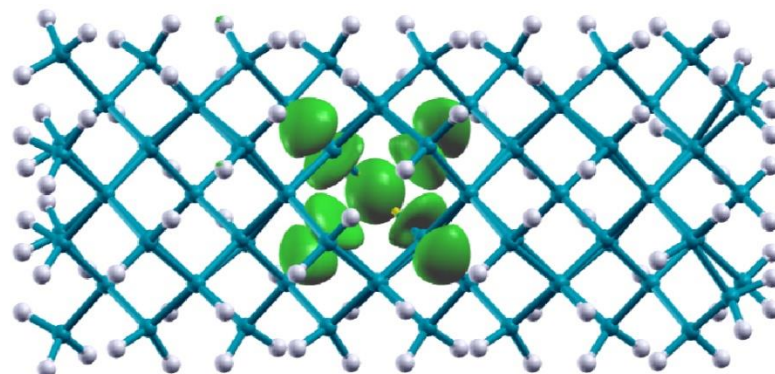


- Three orientations considered
- Diameter: 1.2-1.3 nm
- passivated \rightarrow relaxed

Delocalization of donor wave-function

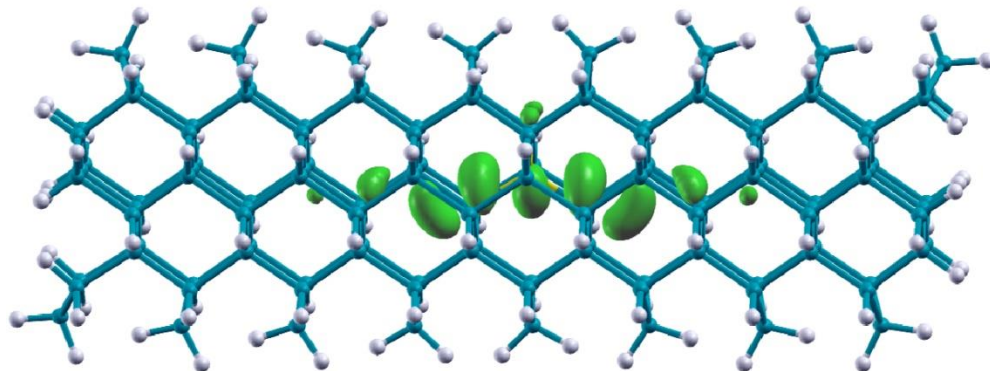
$$a_z \equiv \langle \Psi | \sqrt{z^2} | \Psi \rangle$$

[001]



$$a_z = \int \|\Psi(x, y, z)\|^2 \sqrt{z^2} dx dy dz$$

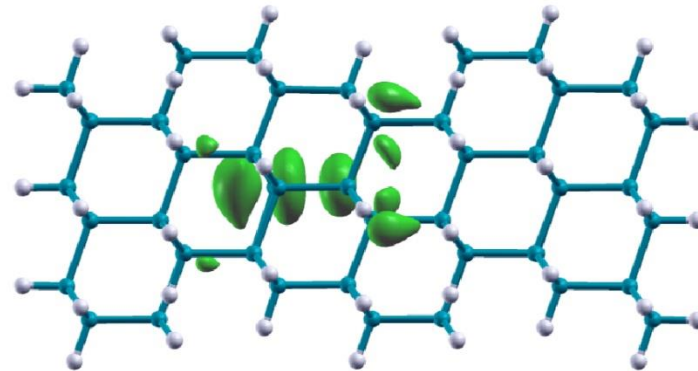
[011]



LUMO of ionized system (Niquet et al, 2010).

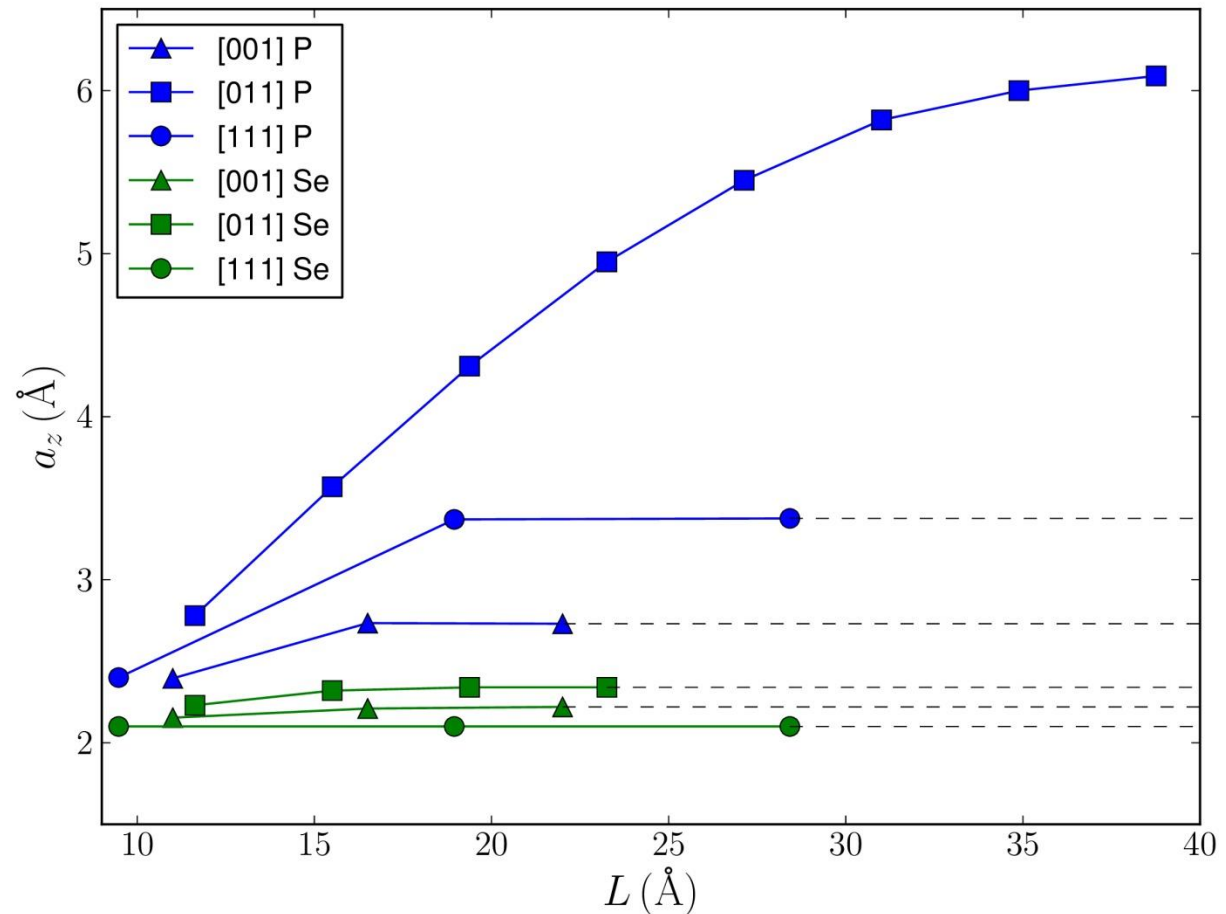
But HOMO of neutral system gives the same qualitative results

[111]



Delocalization of donor wave-function

- The a_z of Se wave-function is computed
- The a_z of Se wave-function for [011] should be extrapolated

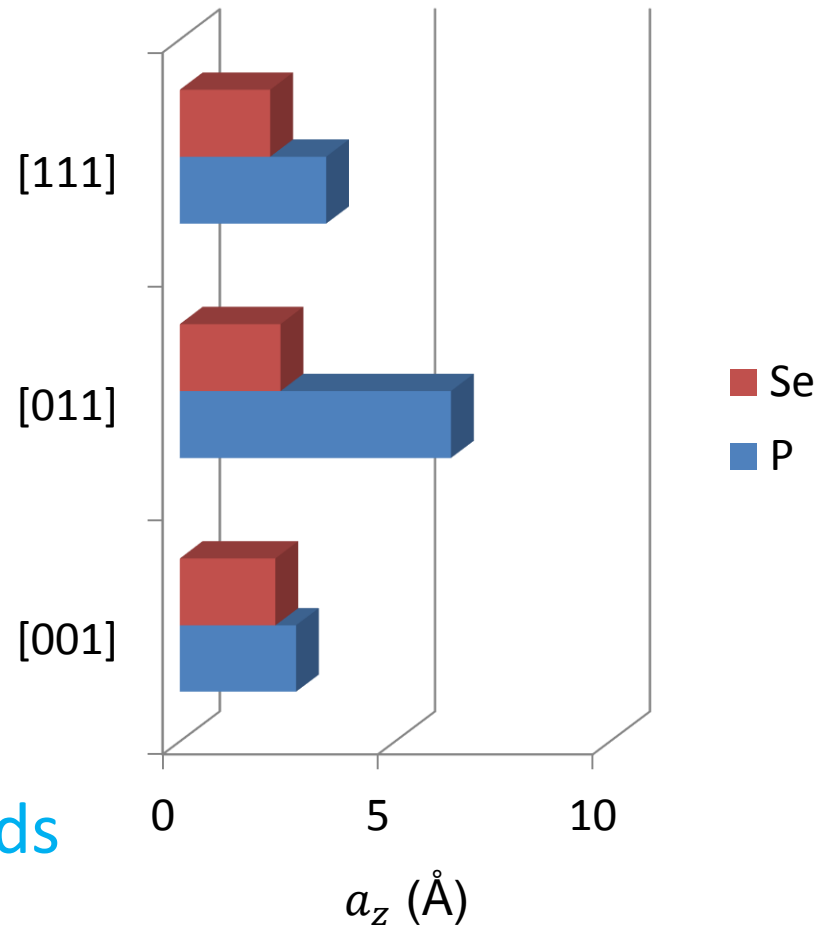
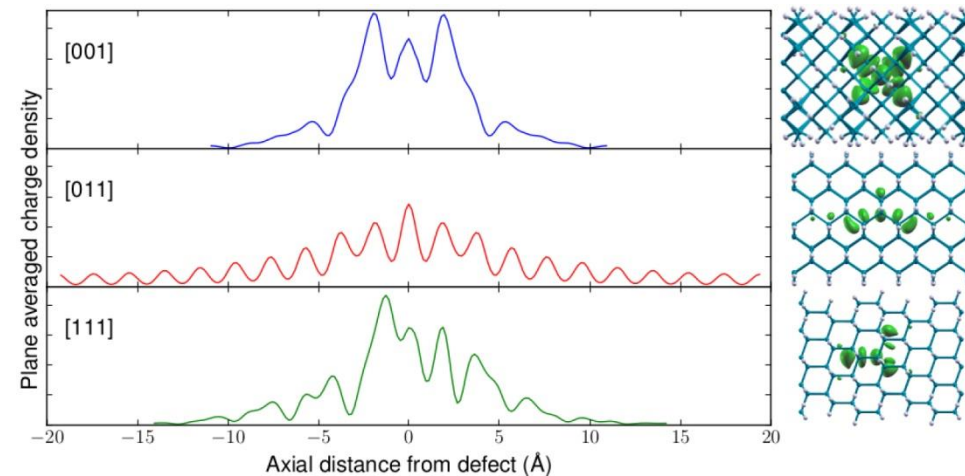


$$f(z, L) = e^{-z^2/a} + c$$

Delocalization of donor wave-function

The large delocalization of P wave-function along [011] direction ...

Si:P bulk $a_z \sim 25 \text{ \AA}$

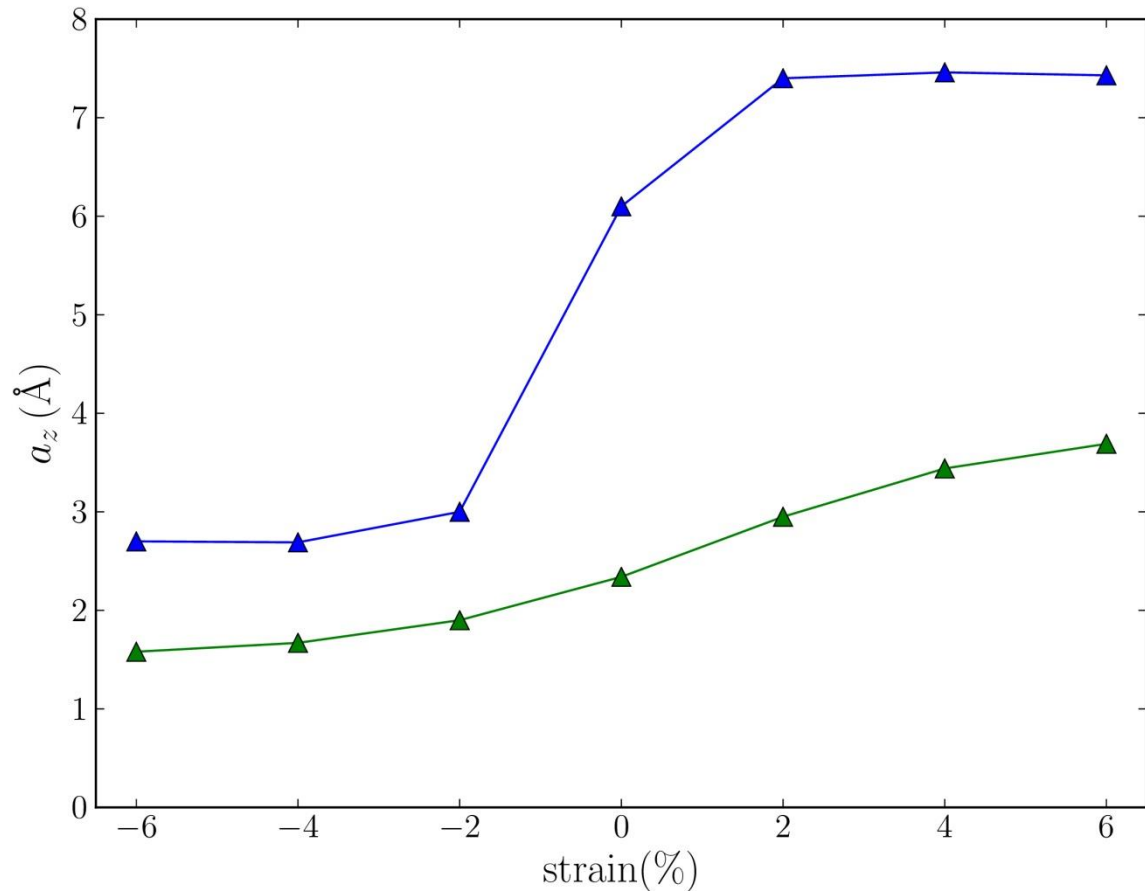


$$a_z^{[001]} < a_z^{[111]} < a_z^{[011]}$$

...we suggest it is a general trends

Strain along the NW axis

- The a_z of Se: non linear dependence of the strain
- The a_z of P: strong dependence



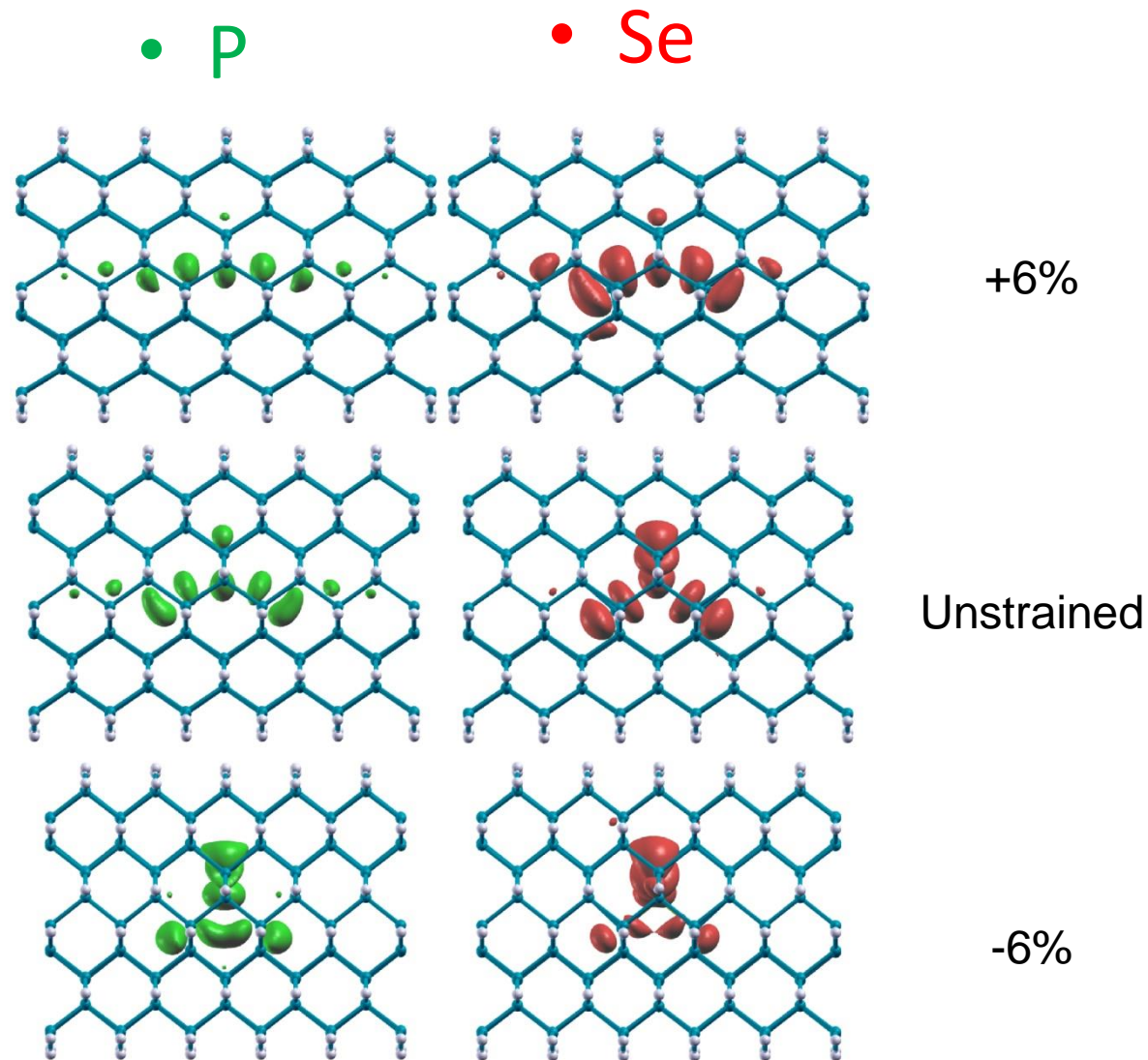
Modification of shallow wave-function by strain

Strain along the NW axis

Quantum computing

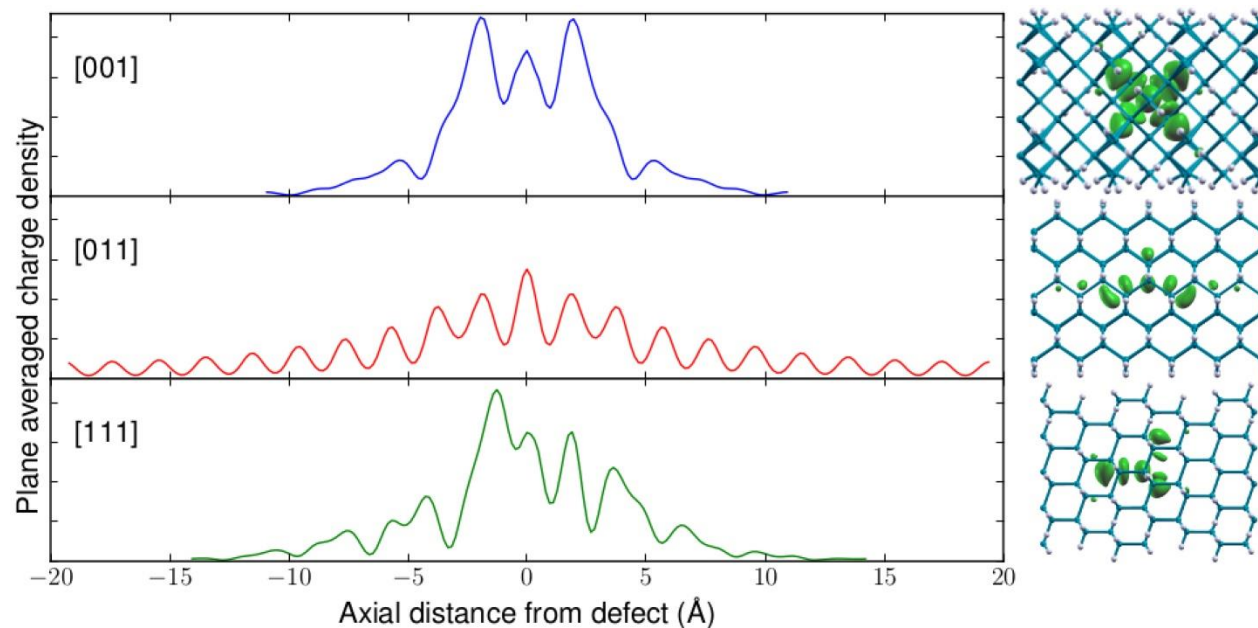


The interaction between neighbour P can be tuned by piezoelectrical actuators



Conclusions

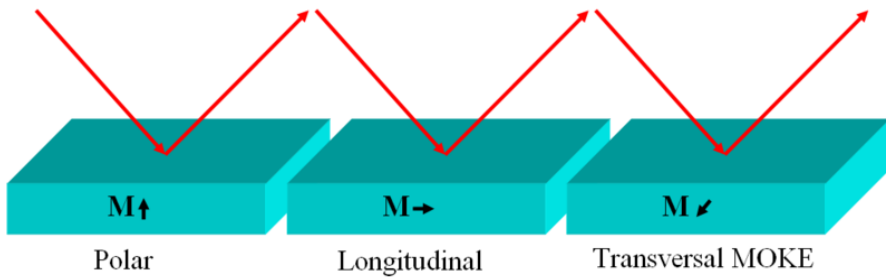
- The [011] is the best direction for nano-electronic and quantum computing applications
- Stress allow to tune delocalization



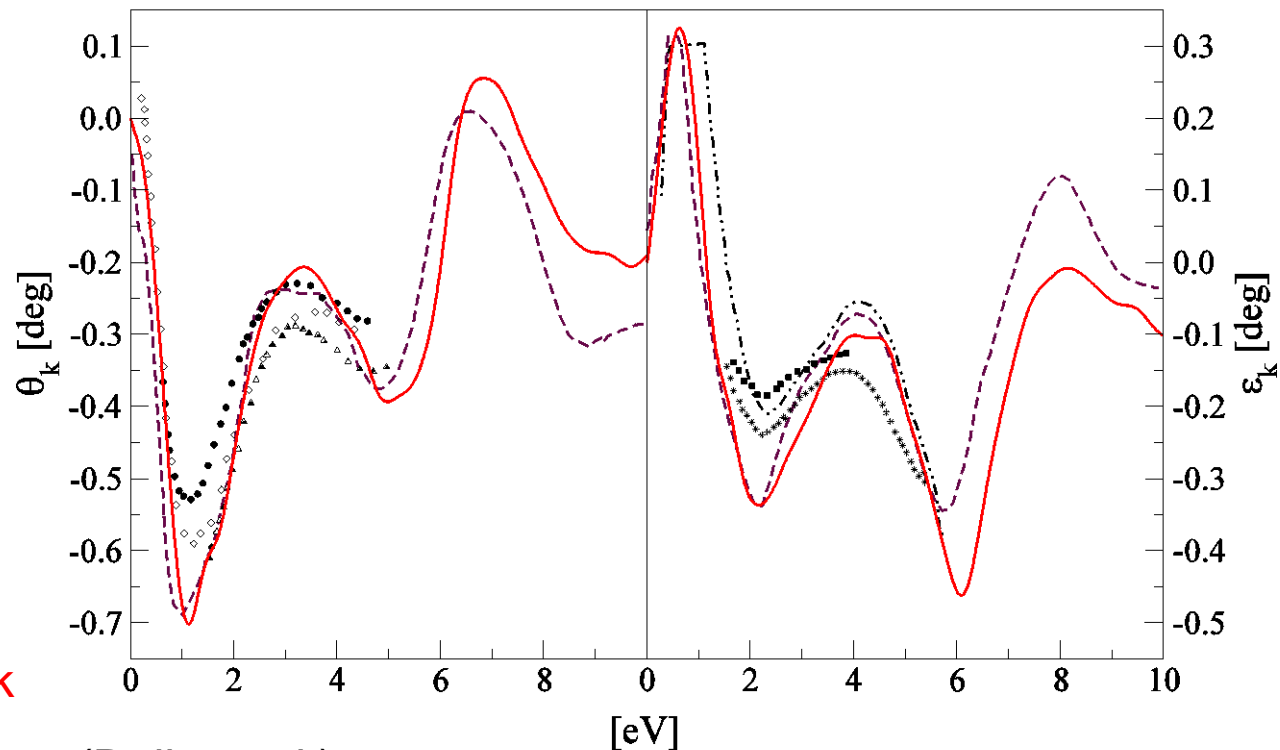
Interazione luce-materia predizioni senza parametri aggiustabili

- Permette l'analisi dei dati sperimentali
- Individua i meccanismi microscopici responsabili di una data proprietà
- Predice quali sono le condizioni ottimali per ottenere un dato fenomeno
- E' più economica di un «vero» esperimento

Ab initio spectroscopy: MOKE



- MOKE spectra by plane-wave pseudopotential techniques
- Simulation of relatively large systems



----- our work

----- all electron (Delin et al.)

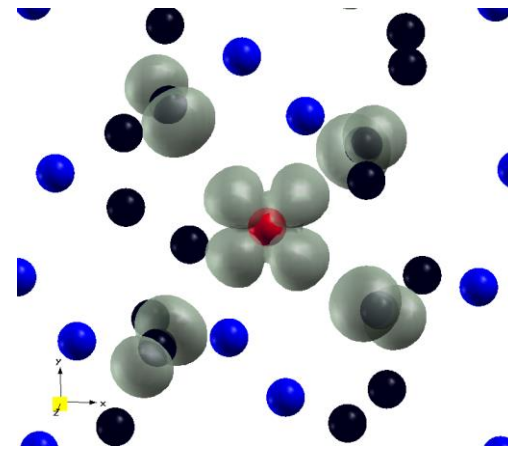
**** experiment

Bulk Fe

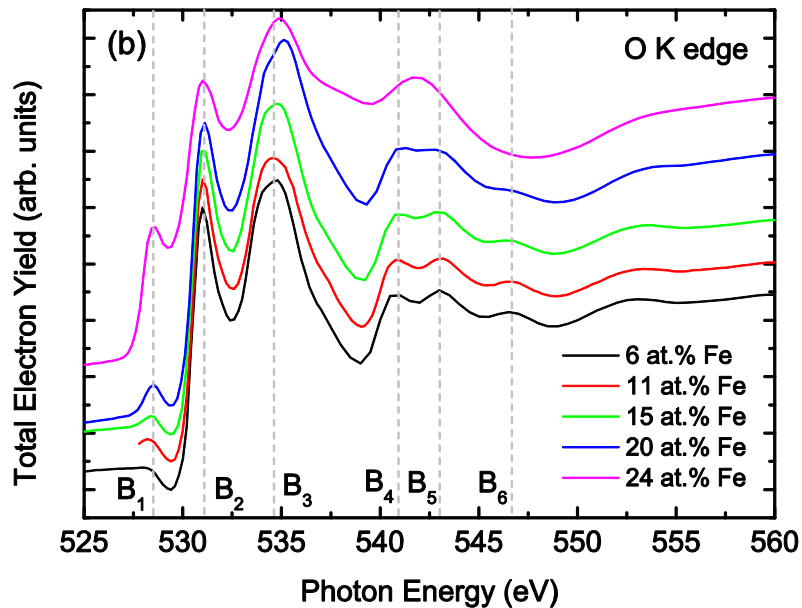
Ab initio spectroscopy: XAS

Interazione luce-materia, predizioni
senza parametri aggiustabili

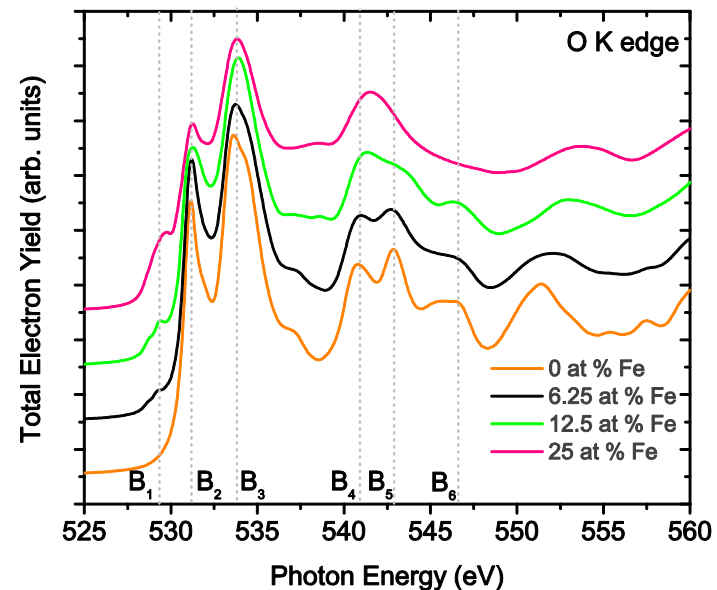
ZrO₂:Fe Diluted Magnetic Oxide for
spintronic applications (film di 29 nm)



Esperimento



Teoria

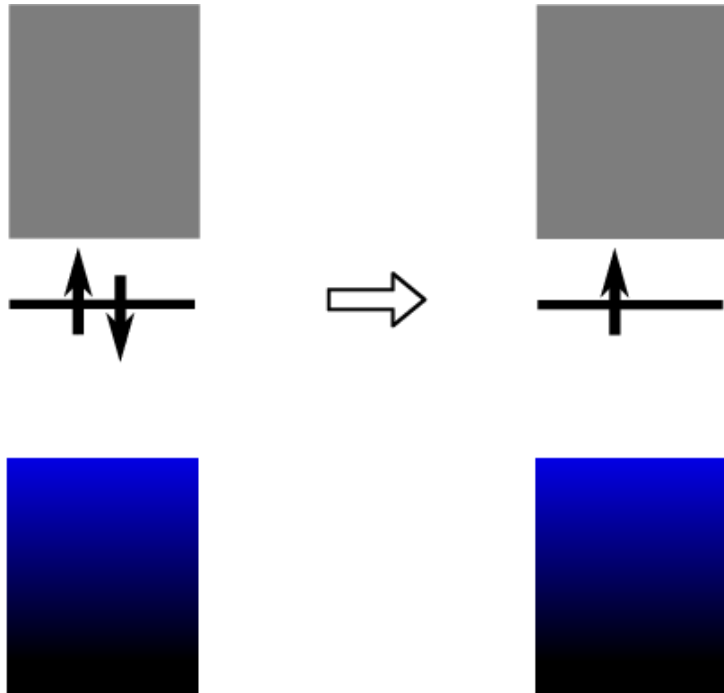


Hyperfine coupling constant: Charged defects

Hyperfine interaction requires a spin density $\neq 0$

Ionization of the impurity

$$\vec{A} = A_{iso} \vec{1} + \vec{A}_{dip}$$

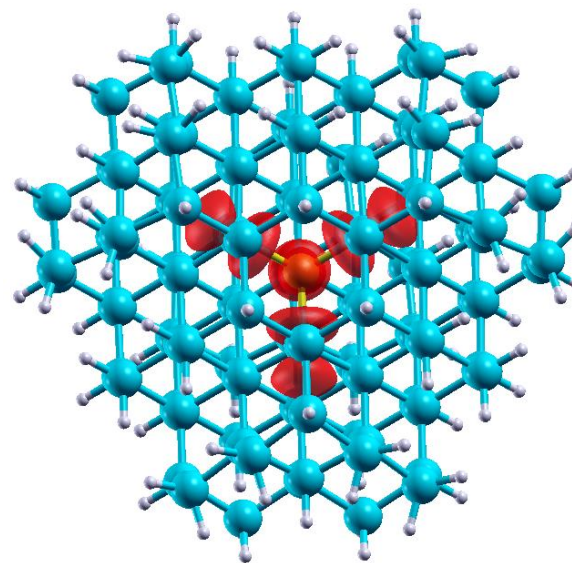
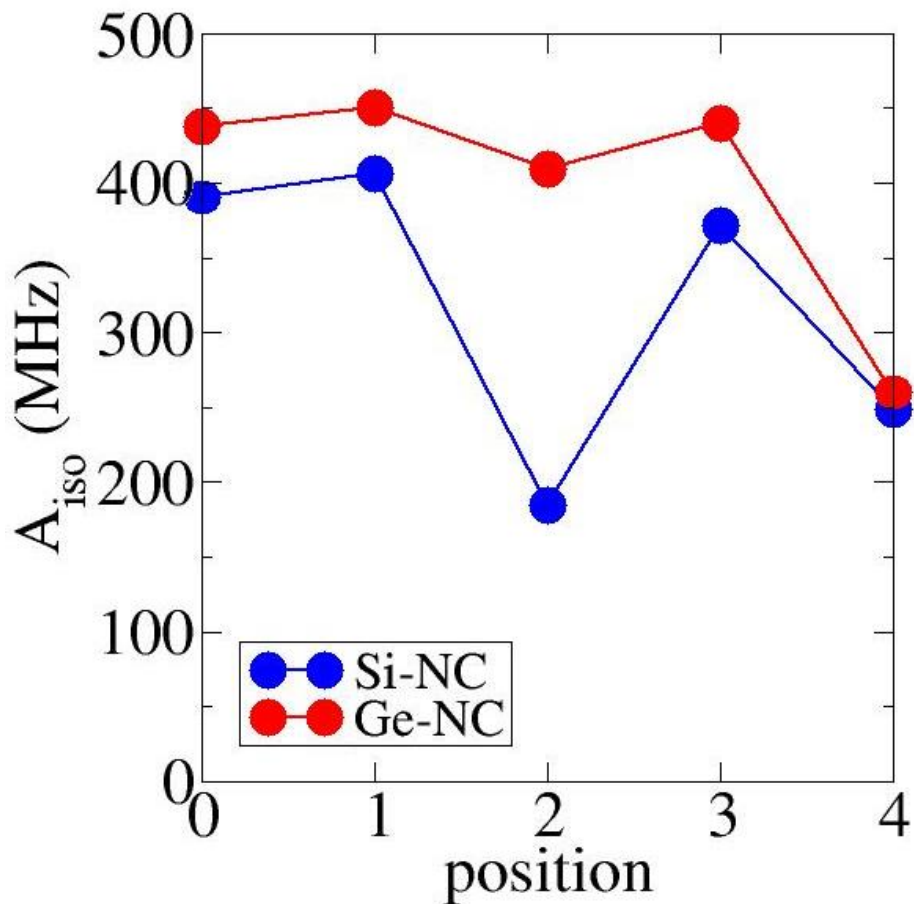


$$A_{iso} = \frac{4\pi g_e \mu_e g_N \mu_N}{3\langle S_z \rangle} \int d^3r n_s(\vec{r}) \delta(\vec{r})$$

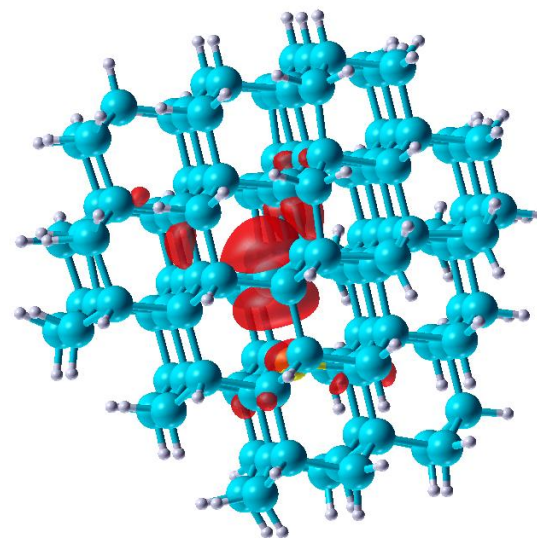
$$A_{dip}^{i,j} = \frac{g_e \mu_e g_N \mu_N}{2\langle S_z \rangle} \int d^3r n_s(\vec{r}) \frac{3r_i r_j - \delta_{i,j} r^2}{r^2}$$

$$A_{dip} = \begin{pmatrix} -b + b' & & \\ & -b - b' & \\ & & 2b \end{pmatrix}$$

Si(Ge) dots:S⁺ contact term



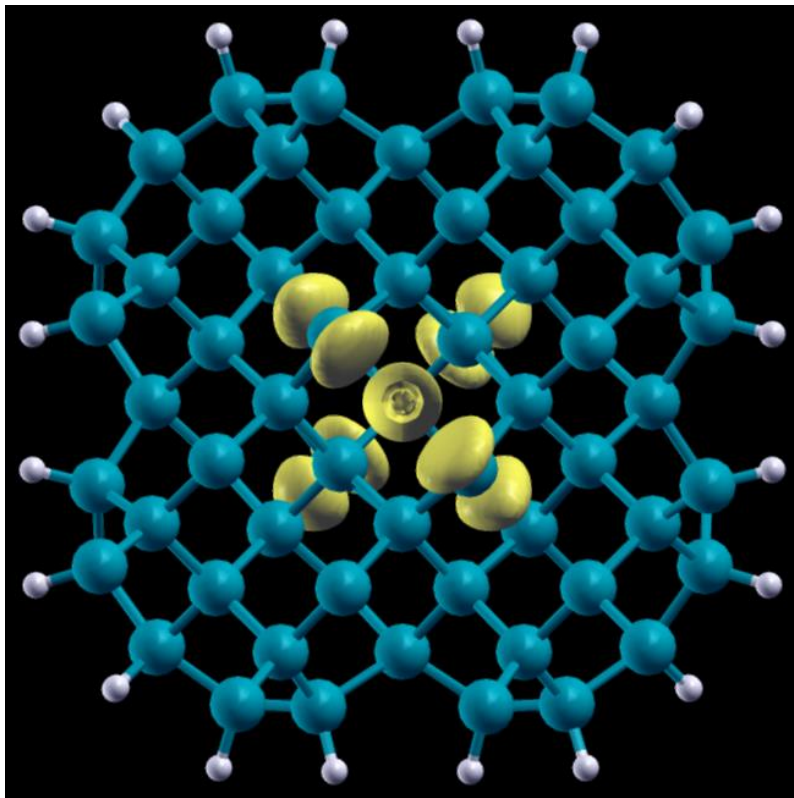
Si-NC:S⁺ (1)



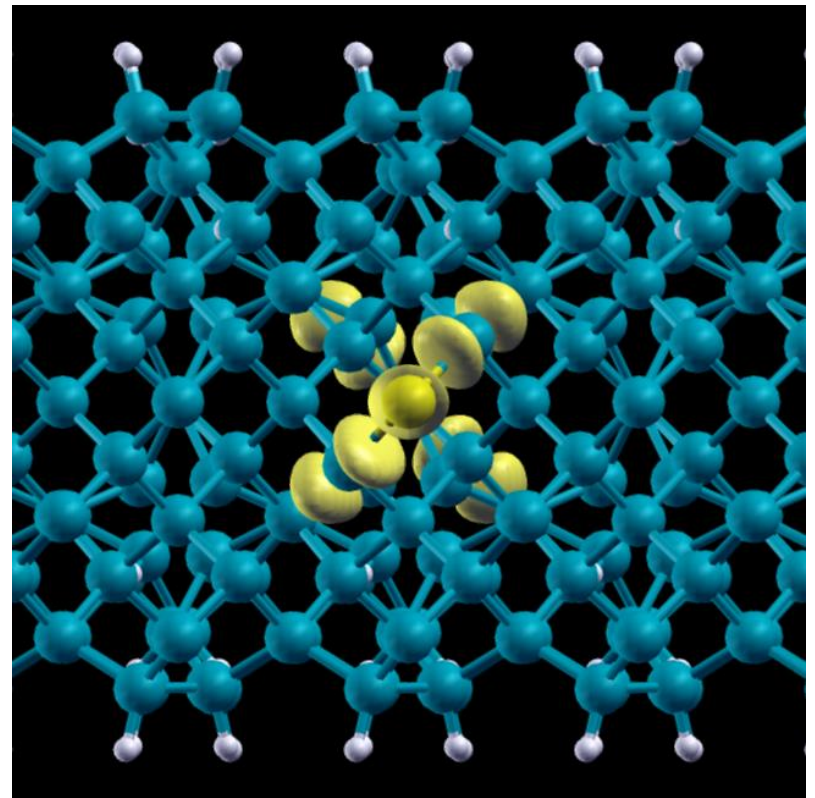
Si-NC:S⁺ (2)

Single atom electronics: Se impurity

Se doped H passivated Si nanowires
(nanoelectronics, quantum computer)



front view

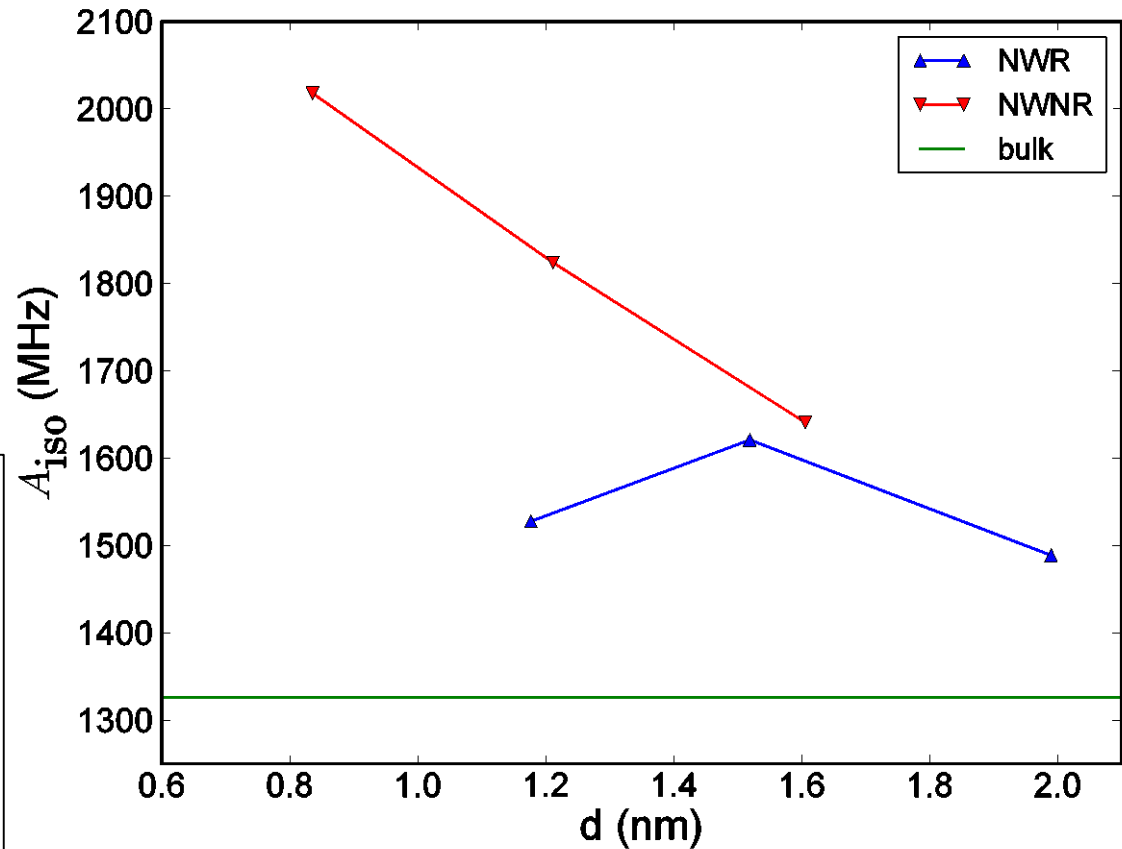
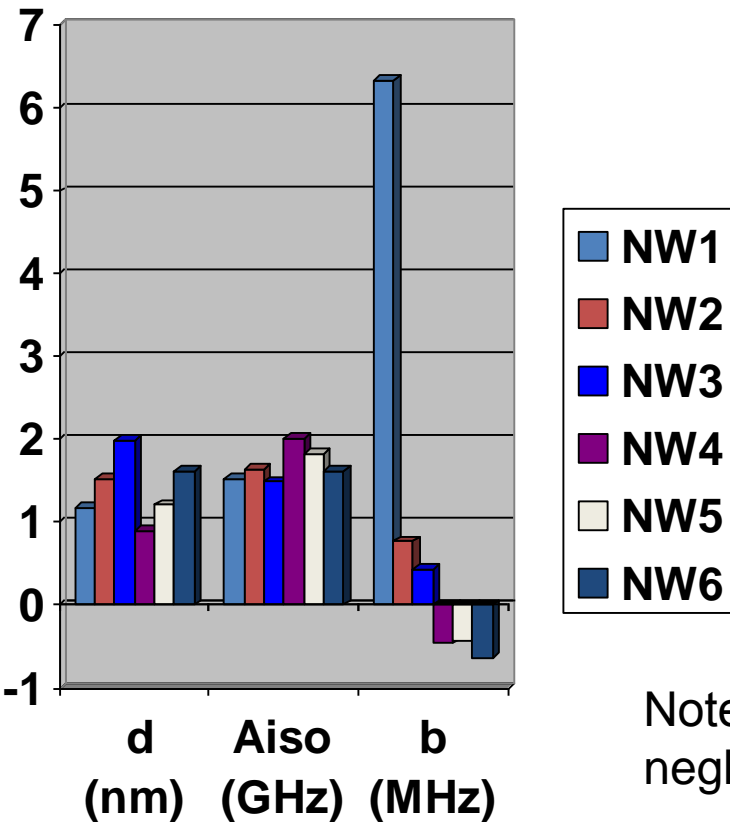


side view

Hyperfine coupling constants: axial Se

Confinement enhances the hyperfine coupling constant

Central impurity
[001]



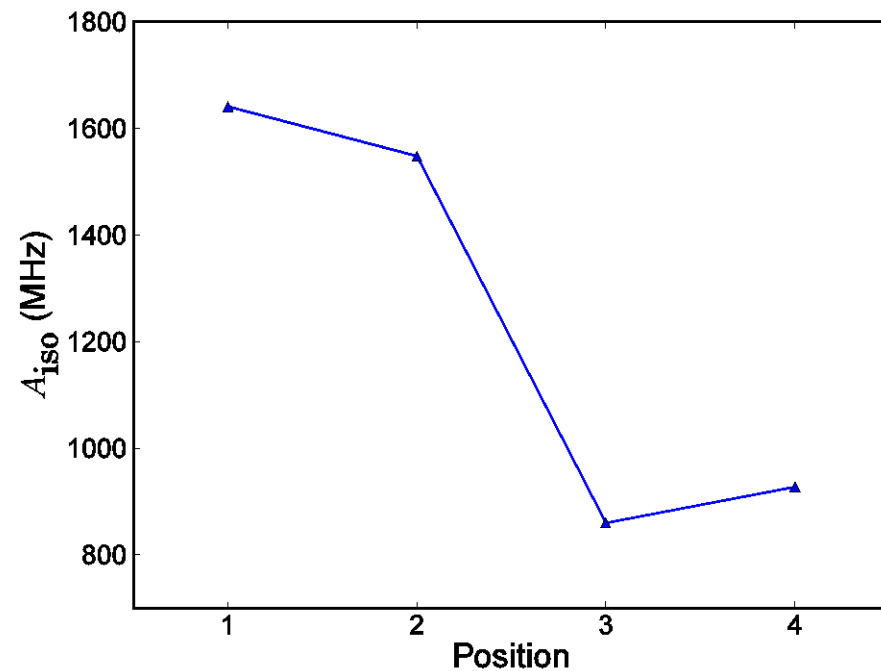
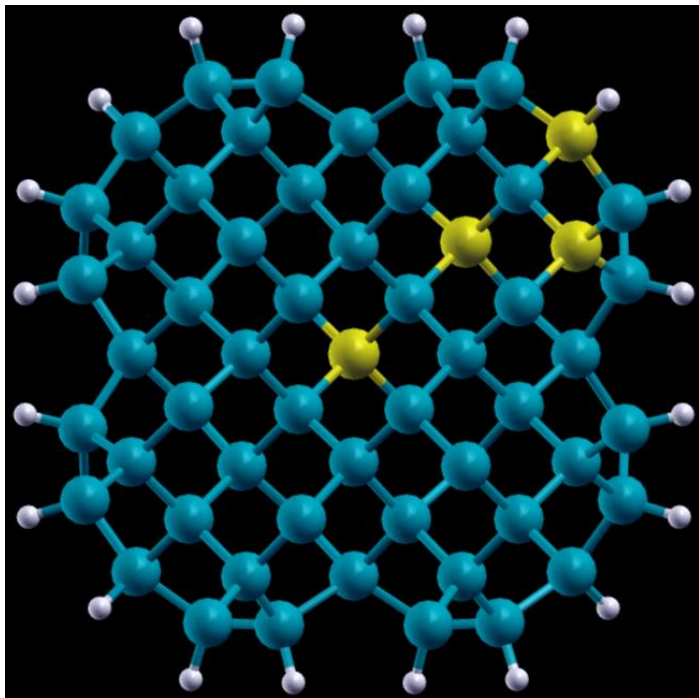
Note: b' is 18.34 MHz for NW1, and negligible (< 0.22) for all the others

Se doped Si-NW

- HFC couples nuclear and electron spin
- Quantum bits (qu-bits) are stored in the nuclear spin of Se atom

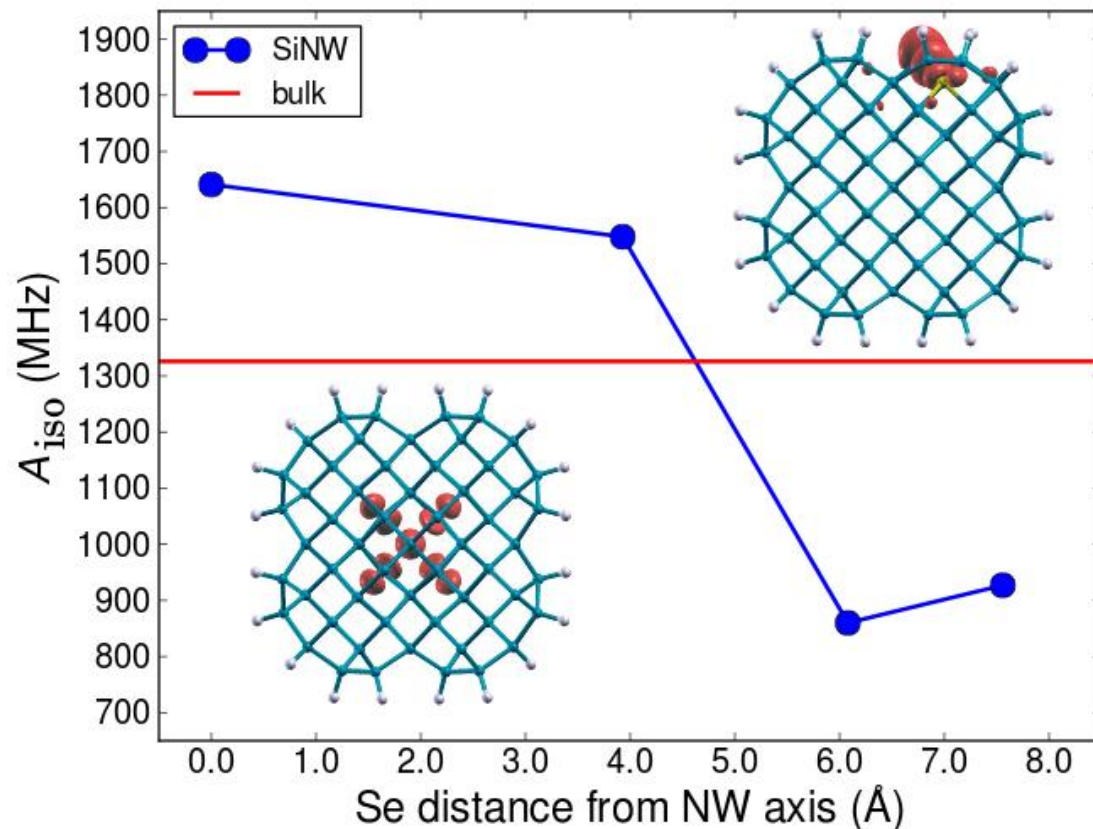
Distortion of NW for small size is significant.

Increase of HFC of about 30% at optimum diameter



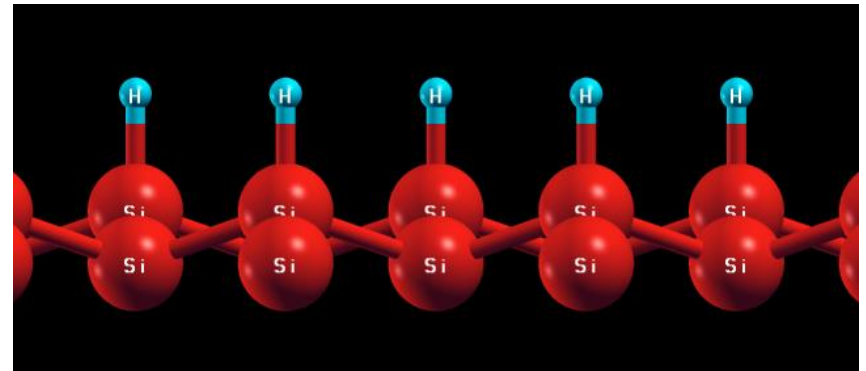
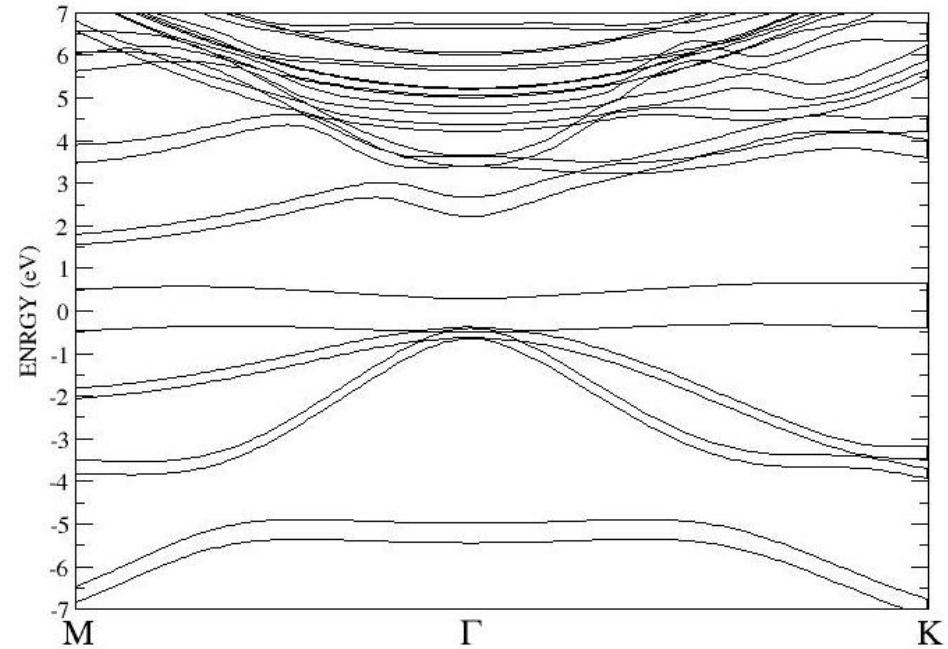
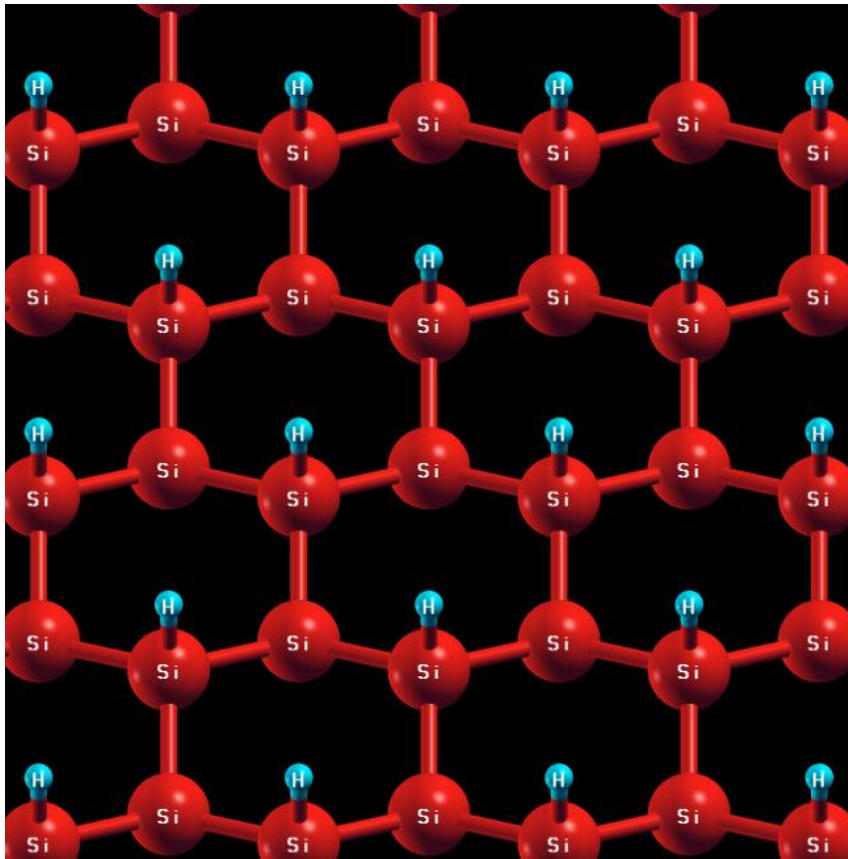
Isotropic Hyperfine Coupling

- STRONG DEPENDENCE OF HYPERFINE CONSTANT ON IMPURITY SITE
- It is possible to DETERMINE the POSITION of the impurity (Se) on the basis of EPR SPECTRA



Silicane: Si@H

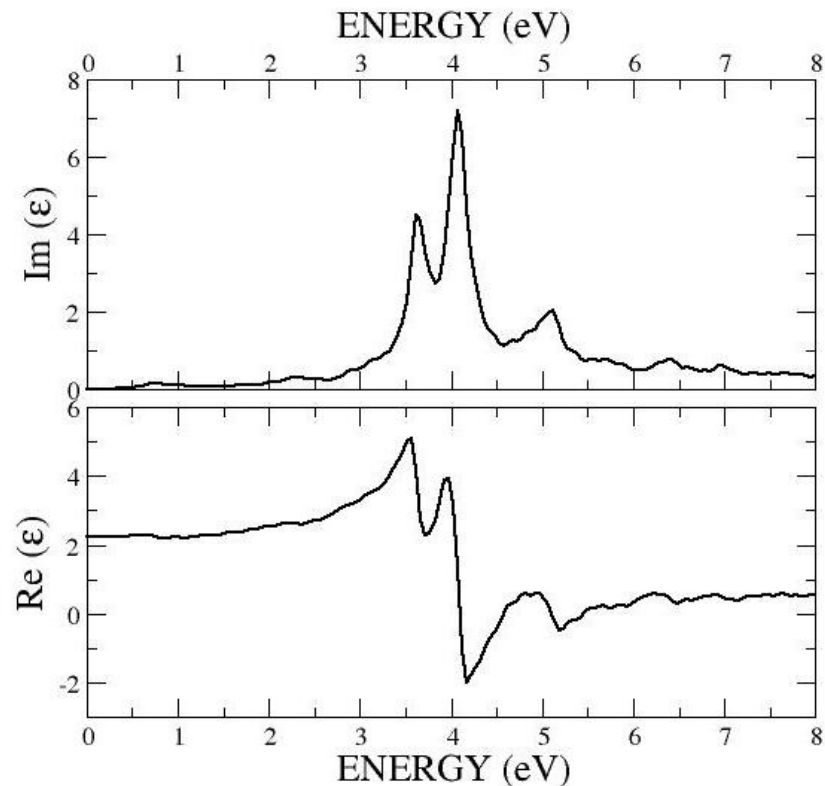
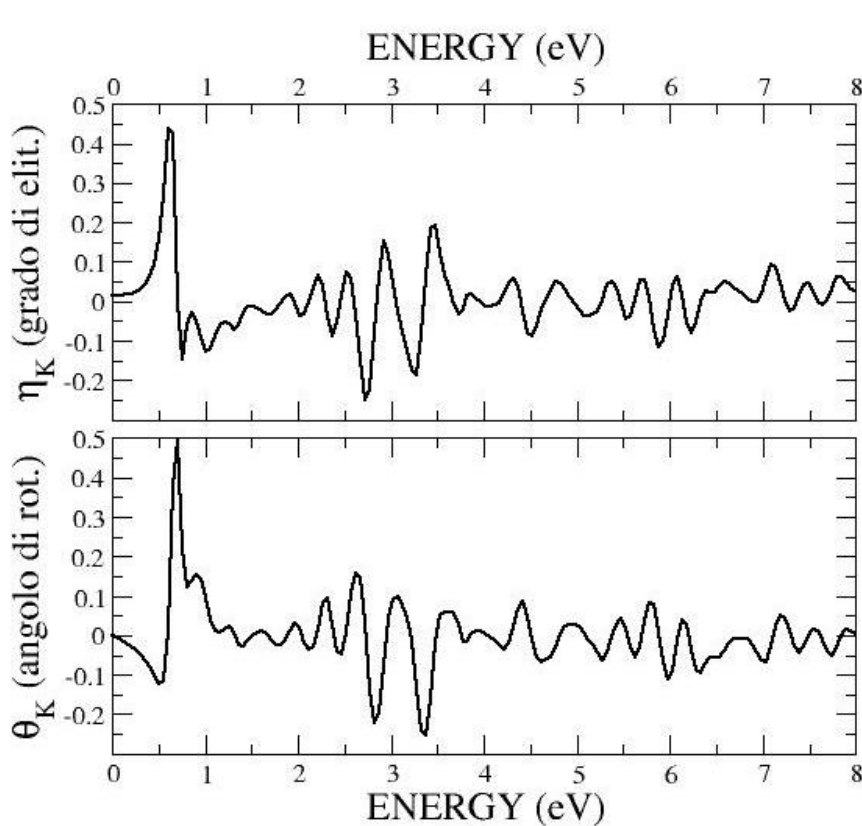
Magnetic Semiconductor



Si@H: Proprietà Ottiche

- Magneto Optical Kerr Effect
- Magnetism

Funzione dielettrica



Conclusions

- The position of the impurity can be determined by comparing EPR spectra with ab initio data
- MOKE signal in 2D for future nano-electronic devices

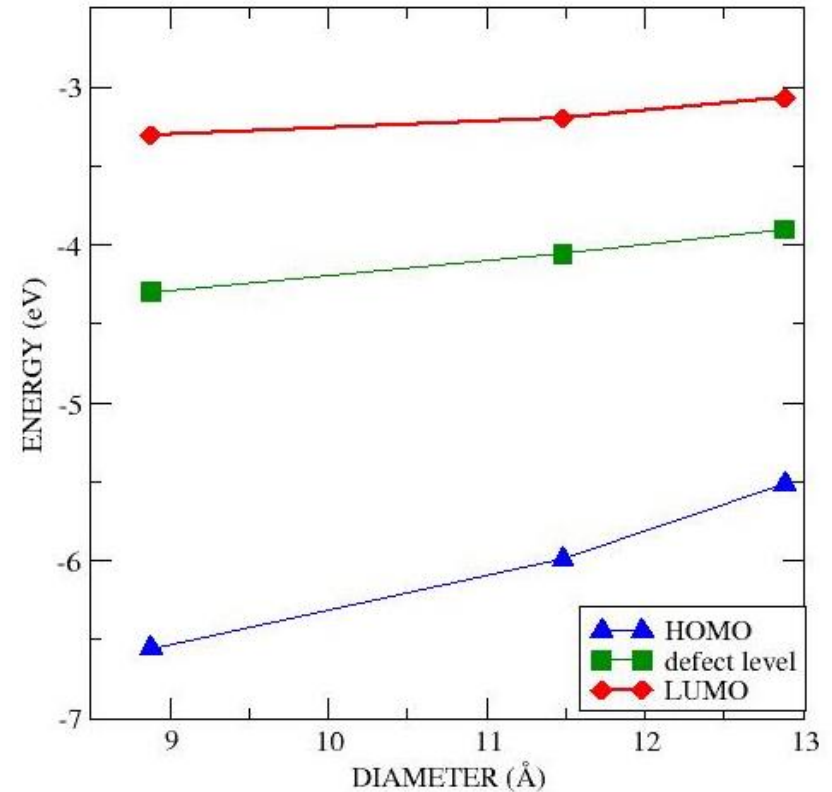
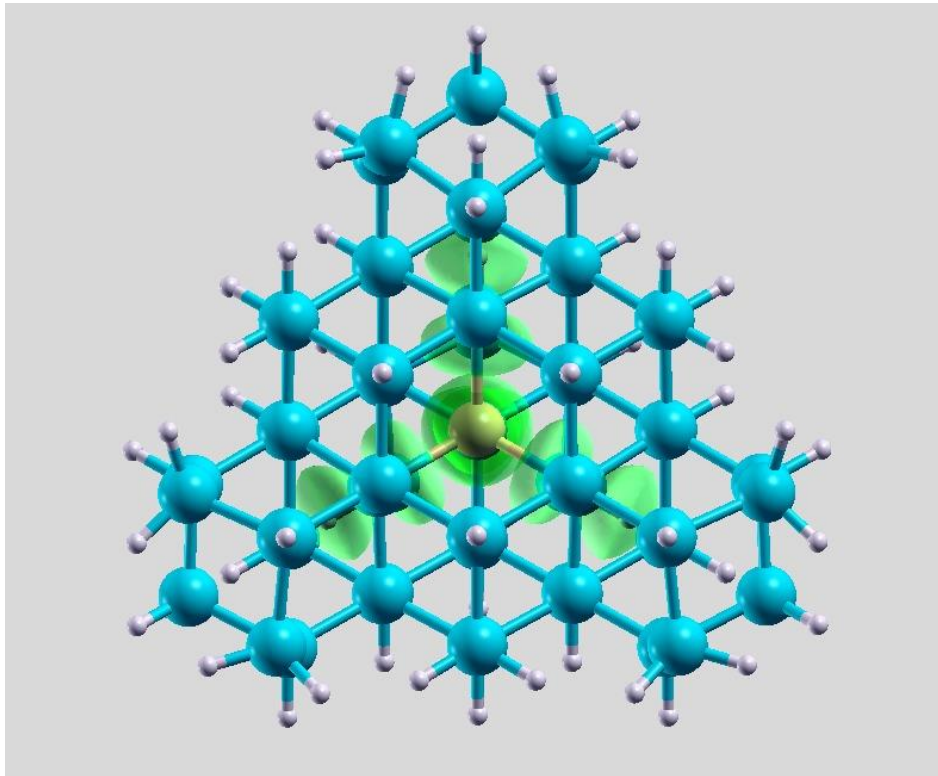
- La Simulazione è MOLTO più economica dell'esperimento
- Possiamo «inventare» nuovi materiali e modificarne le proprietà per una nuova elettronica.

A special thanks to

- G. Petretto, A. Masse (IMM-CNR, University of Milano Bicocca)
- L. Marchetti, P. Rosa (IMM-CNR, University of Milano Statale)
- D.Douma, D.Sangalli (IMM-CNR)
- M. Fanciulli (UNIMIB, MDM) and to all experimentalists at the MDM laboratory.
- LISA for computational resources

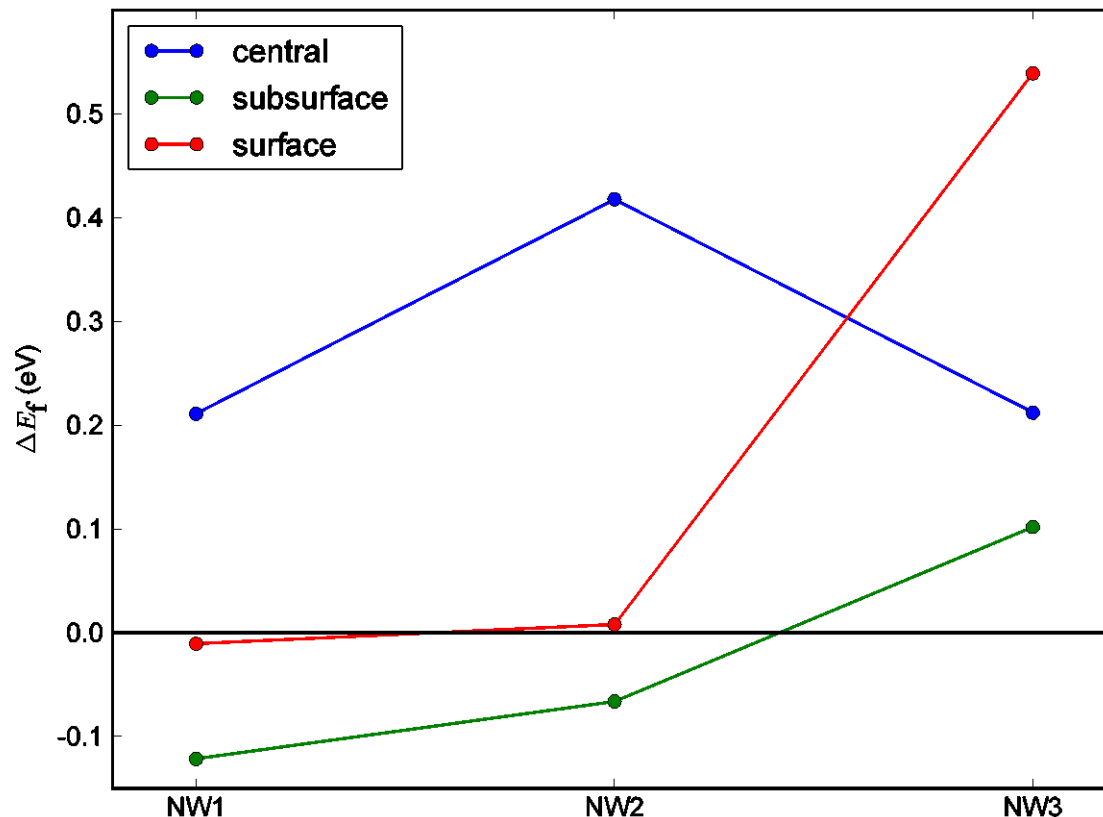
... and you for your attention !!!

S doped Si Nano Dots



Se doped Si NW: Formation Energy

- Subsurface position is energetically favoured (at least for small diameter)
- Effect of distortion for small diameters



Stability of ionized Se

- Formation energy of the defect on the axis of the nanowire as a function of the chemical potential.
- The three graphs represent the three different nanowires with diameter 1.2 nm, 1.5 nm, 2.0 nm respectively.
- The zero value is the calculated value of the formation energy of Se defect in bulk Si.

